

Resource Summary Report

Generated by [RRID](#) on Aug 5, 2026

Kratos: AXIS-165 XPS Surface Analysis System

RRID:SCR_020207

Type: Tool

Proper Citation

Kratos: AXIS-165 XPS Surface Analysis System (RRID:SCR_020207)

Resource Information

URL: <https://www.kratos.com/products/axis-nova>

Proper Citation: Kratos: AXIS-165 XPS Surface Analysis System (RRID:SCR_020207)

Description: AXIS Nova combines XPS imaging and spectroscopic capabilities with a highly automated, large sample handling system and is the next generation of AXIS Nova spectrometer. The AXIS Nova is based on Kratos, AXIS technology comprising: magnetic and electrostatic transfer lenses; co-axial electron-only charge neutralisation; spherical mirror and hemispherical electron energy analysers. Kratos developed innovations such as the delay-line detector for spectroscopy and imaging modes and high energy X-ray excitation sources ensure the AXIS Nova is capable of performing in the most demanding research and development environments.

Resource Type: instrument resource

Keywords: Kratos, Surface Analysis System, Instrument Equipment, USEdit

Availability: Commercially available

Resource Name: Kratos: AXIS-165 XPS Surface Analysis System

Resource ID: SCR_020207

Alternate IDs: Model_Number_AXIS-165 XPS

Record Creation Time: 20220129T080349+0000

Record Last Update: 20260801T190653+0000

Ratings and Alerts

No rating or validation information has been found for Kratos: AXIS-165 XPS Surface Analysis System.

No alerts have been found for Kratos: AXIS-165 XPS Surface Analysis System.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.